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N-channel TrenchMOS intermediate level FET

Rev. 03 — 12 October 2010

Product data sheet

1. Product profile

1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for standard and logic level gate drive sources

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

1.4 Quick reference data

Table 1. Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

Table 1.	Quick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	40	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	[1]	-	-	100	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	158	W
Static cha	racteristics						
R _{DSon}	drain-source on-state resistance	$\label{eq:GS} \begin{array}{l} V_{GS} = 10 \; V; I_{D} = 25 \; A; \\ T_{j} = 25 \; ^{\circ}C; see \; \underline{Figure \; 11} \end{array}$		-	3.84	4.8	mΩ



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Table 1.	Quick reference data	continued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 100 \text{ A}; V_{\text{sup}} \leq 40 \text{V}; \\ R_{\text{GS}} &= 50 \Omega; V_{\text{GS}} = 10 \text{V}; \\ T_{j(\text{init})} &= 25 ^{\circ}\text{C}; \text{ unclamped} \end{split} $	-	-	179	mJ
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure } 13}{\text{see } \frac{\text{Figure } 14}{\text{Figure } 14}}$	-	25.9	-	nC

[1] Continuous current is limited by package.

2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		5
2	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

SOT78A (TO-220AB)

3. Ordering information

Table 3.	Ordering	information
	e ao ing	

Type number	Package		
	Name	Description	Version
BUK654R8-40C	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

$\begin{split} & V_{GS} & gate-source voltage & DC & 11 & -16 & 16 \\ \hline Pulsed & 21 & -20 & 20 \\ \hline Pulsed & 21 & -20 & 20 \\ \hline Pulsed & 21 & -20 & 20 \\ \hline T_{mb} = 25 ^\circ C; V_{GS} = 10 V; see Figure 1 & 13 & - & 10 \\ \hline T_{mb} = 100 ^\circ C; V_{GS} = 10 V; see Figure 1 & - & 88 \\ \hline D_{DM} & peak drain current & T_{mb} = 25 ^\circ C; t_p \leq 10 \mu s; pulsed; & - & 50 \\ see Figure 3 & - & 15 \\ \hline T_{stg} & storage temperature & -55 & 17 \\ \hline T_{stg} & storage temperature & -55 & 17 \\ \hline Source-drain diode & & & \\ \hline I_S & source current & T_{mb} = 25 ^\circ C & 13 & - & 10 \\ \hline I_SM & peak source current & T_{mb} = 25 ^\circ C & 13 & - & 10 \\ \hline I_{SM} & peak source current & T_{p} \leq 10 \mu s; pulsed; T_{mb} = 25 ^\circ C & - & 50 \\ \hline Avalanche ruggedness & & \\ \hline E_{DS(AL)S} & non-repetitive drain-source \\ avalanche energy & V_{GS} = 10 V; T_{j(init)} = 25 ^\circ C; unclamped & - & 17 \\ \hline \end{array}$	bol	Parameter	Conditions		Min	Max	Unit
$\begin{array}{c} \label{eq:rescaled} \begin{tabular}{ c c c c } \hline Pulsed & P$		drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	40	V
$I_{D} = I_{D} = I_{D$		gate-source voltage	DC	<u>[1]</u>	-16	16	V
$\begin{tabular}{ c c c c } \hline T_{mb} & = 100\ ^\circ C;\ V_{GS} & = 10\ V;\ see\ Figure\ 1 & - & 88 \\ \hline T_{mb} & = 100\ ^\circ C;\ V_{GS} & = 10\ V;\ see\ Figure\ 1 & - & 88 \\ \hline T_{mb} & = 25\ ^\circ C;\ t_p & \leq 10\ \mu s;\ pulsed;\ & - & 50 \\ see\ Figure\ 3 & source;\ see\ Figure\ 3 & - & 15 \\ \hline T_{stg} & storage\ temperature & & -55 & 17 \\ \hline T_{stg} & storage\ temperature & & -55 & 17 \\ \hline T_{j} & junction\ temperature & & -55 & 17 \\ \hline Source-drain\ diode & & & & \\ \hline I_S & source\ current & T_{mb} & = 25\ ^\circ C & $$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$			Pulsed	[2]	-20	20	V
$ \begin{array}{cccc} I_{DM} & \mbox{peak drain current} & T_{mb} = 25 \ {}^\circ\mbox{C}; \ t_p \leq 10 \ \mu\mbox{s; pulsed;} & - & 50 \ \ see \ Figure 3 & 50 \ \ see \ Figure 2 & - & 15 \ \ T_{stg} & storage temperature & -55 & 17 \ \ T_j & junction temperature & -55 & 17 \ \ Source-drain diode & -55 & 10 \ \ Source-drain diode & -55 & 10 \ \ Source-drain diode & -55 & -55 \ \ Source-drain diode & -55 \ \ Source-drai$		drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{see } \frac{\text{Figure 1}}{\text{Figure 1}}$	<u>[3]</u>	-	100	А
see Figure 3 P_{tot} total power dissipation $T_{mb} = 25 ^{\circ}C$; see Figure 2- 15 T_{stg} storage temperature-5517 T_j junction temperature-5517Source-drain diodeIssource current $T_{mb} = 25 ^{\circ}C$ [3]- 10Issource current $T_p \le 10 \mu s$; pulsed; $T_{mb} = 25 ^{\circ}C$ - 50Avalanche ruggednessIb = 100 A; $V_{sup} \le 40 V$; $R_{GS} = 50 \Omega$; colspan="2">- 17EDS(AL)Snon-repetitive drain-source avalanche energyIb = 100 A; $V_{sup} \le 40 V$; $R_{GS} = 50 \Omega$; colspan="2">- 17			T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 1		-	88	А
$\begin{array}{cccc} T_{stg} & storage temperature & -55 & 17 \\ T_{j} & junction temperature & -55 & 17 \\ \hline Source-drain diode & & & \\ I_{S} & source current & T_{mb} = 25 \ ^{\circ}C & \ ^{[3]} & - & 10 \\ I_{SM} & peak source current & t_{p} \leq 10 \ \mu s; pulsed; T_{mb} = 25 \ ^{\circ}C & - & 50 \\ \hline Avalanche ruggedness & & & \\ \hline E_{DS(AL)S} & non-repetitive drain-source & I_{D} = 100 \ A; \ V_{sup} \leq 40 \ V; \ R_{GS} = 50 \ \Omega; \\ V_{GS} = 10 \ V; \ T_{j(init)} = 25 \ ^{\circ}C; unclamped & - & 17 \\ \hline \end{array}$		peak drain current	····• • · ·		-	500	A
$\begin{array}{c cccc} T_{j} & junction \ temperature & -55 & 17 \\ \hline \begin{tabular}{lllllllllllllllllllllllllllllllllll$		total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	158	W
$\begin{tabular}{ c c c } \hline Source-drain diode \\ \hline I_S & source current & T_{mb} = 25 \ ^\circ C & $[3]$ & - 10 \\ \hline I_{SM} & peak source current & t_p \leq 10 \ \mu s; pulsed; T_{mb} = 25 \ ^\circ C & - 50 \\ \hline Avalanche ruggedness \\ \hline E_{DS(AL)S} & non-repetitive drain-source & I_D = 100 \ A; \ V_{sup} \leq 40 \ V; \ R_{GS} = 50 \ \Omega; \\ V_{GS} = 10 \ V; \ T_{j(init)} = 25 \ ^\circ C; \ unclamped \\ \hline \end{array} \begin{tabular}{lllllllllllllllllllllllllllllllllll$		storage temperature			-55	175	°C
$\label{eq:ls} \begin{array}{c c} I_{S} & \text{source current} & T_{mb} = 25 \ ^{\circ}\text{C} & \fbox{3} & - & 10 \\ \hline I_{SM} & \text{peak source current} & t_{p} \leq 10 \ \mu\text{s; pulsed; } T_{mb} = 25 \ ^{\circ}\text{C} & - & 50 \\ \hline \begin{array}{c} \textbf{Avalanche ruggedness} & & & \\ \hline \\ E_{DS(AL)S} & \text{non-repetitive drain-source} & I_{D} = 100 \ \text{A; } V_{sup} \leq 40 \ \text{V; } R_{GS} = 50 \ \Omega; \\ V_{GS} = 10 \ \text{V; } T_{j(init)} = 25 \ ^{\circ}\text{C; unclamped} & & \\ \end{array} \right.$		junction temperature			-55	175	°C
$\begin{split} & \text{Imp} = 26 \text{ e}^{-10} $	ce-drain	diode					
Avalanche ruggedness $E_{DS(AL)S}$ non-repetitive drain-source avalanche energy $I_D = 100 \text{ A}; V_{sup} \le 40 \text{ V}; R_{GS} = 50 \Omega;$ $V_{GS} = 10 \text{ V}; T_{j(init)} = 25 ^{\circ}C;$ unclamped17		source current	T _{mb} = 25 °C	[3]	-	100	А
		peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	500	А
avalanche energy $V_{GS} = 10 \text{ V}; \text{ T}_{j(init)} = 25 \text{ °C}; \text{ unclamped}$	anche rug	ggedness					
	AL)S	•			-	179	mJ
E _{DS(AL)R} repetitive drain-source avalanche energy	AL)R	•		<u>[4][5][6]</u>	-	-	J

[1] -16V accumulated duration not to exceed 168 hrs.

[2] Accumulated pulse duration not to exceed 5mins.

[3] Continuous current is limited by package.

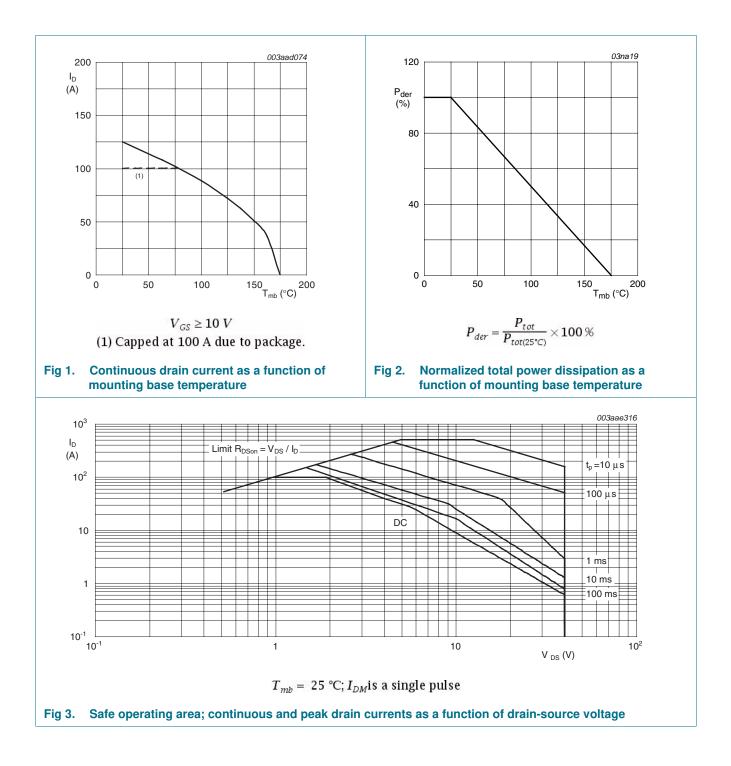
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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5. Thermal characteristics

Table J.						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.95	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W

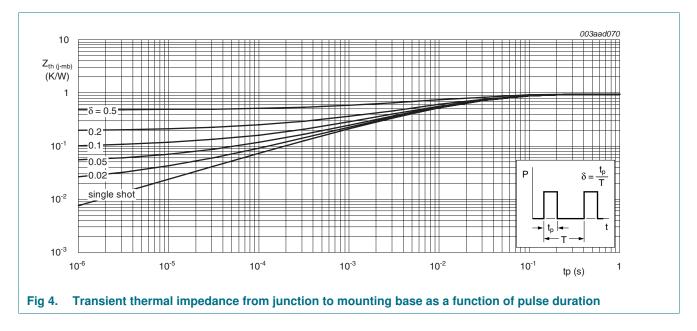


Table 5. Thermal characteristics

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6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ\text{C}$	40	-	-	V
	voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	36	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		$\label{eq:ID} \begin{split} I_D = 1 \mbox{ mA; } V_{DS} = V_{GS}; T_j = -55 \mbox{ °C}; \\ see \mbox{ Figure 9} \end{split}$	-	-	3.3	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see Figure 9	0.8	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
I _{GSS}	gate leakage current $V_{DS} = 0 V; V_{GS} = 20 V; T_j = 25 °C$	-	2	100	nA	
		$V_{DS} = 0 \ V; \ V_{GS} = -20 \ V; \ T_j = 25 \ ^{\circ}C$	-	2	100	nA
R _{DSon} drain-source on-state resistance	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 11</u>	-	3.84	4.8	mΩ
		V _{GS} = 5 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 11</u>	-	5.2	6.5	mΩ
		V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 11</u>	-	5.9	7.9	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	10.1	mΩ
Dynamic	characteristics					
Q _{G(tot)} total gate charge	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	88	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	50.5	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	14.6	-	nC
Q _{GD}	gate-drain charge	see <u>Figure 13;</u> see <u>Figure 14</u>	-	25.9	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	3900	5200	pF
C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 15}{15}$	-	512	614	pF
C _{rss}	reverse transfer capacitance		-	350	480	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	23	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega$	-	52	-	ns
t _{d(off)}	turn-off delay time		-	164	-	ns
t _f	fall time		-	77	-	ns
L _D	internal drain inductance	from drain lead 6 mm from package to centre of die ; $T_j = 25 \text{ °C}$	-	4.5	-	nH
L _S	internal source inductance	from source lead to source bond pad ; $T_j = 25 \ ^\circ C$	-	7.5	-	nH

Symbol

Source-drain diode

BUK654R8-40C

Unit

Max

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Тур

Min

V _{SD}	source-drain voltage	$I_S = 25 \text{ A}; \text{ V}_{GS} = 0 \text{ V}; \text{ T}_j = 25 \text{ °C};$ see <u>Figure 16</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ d}I_{S}/\text{d}t = -100 \text{ A}/\mu\text{s};$	-	42	-	ns
Qr	recovered charge	$V_{GS} = 0 V; V_{DS} = 25 V$	-	65	-	nC
100 (A) 75 50 25	10.0 5.0 4.5 V _{GS} (V	3.8 60 3.6 40 3.4 20 3.2 0	= 175 °C	T _j = 25 °C	003aae319	
	$T_j = 25 ^{\circ}C$ Output characteristics: drain cur function of drain-source voltage;		$V_{DS} > I_D \times H$ paracteristics gate-source	s: drain d		
	00)3aae320		,	003aae347	
100 ^g fs (S) 80		20 R _{DSon} (mΩ) 15				
		10				
40 20						
			10	15	V _{GS} (V) ²⁰)
20		5 0 0 0 5	10	,	V _{GS} (V) ²⁰)

Conditions

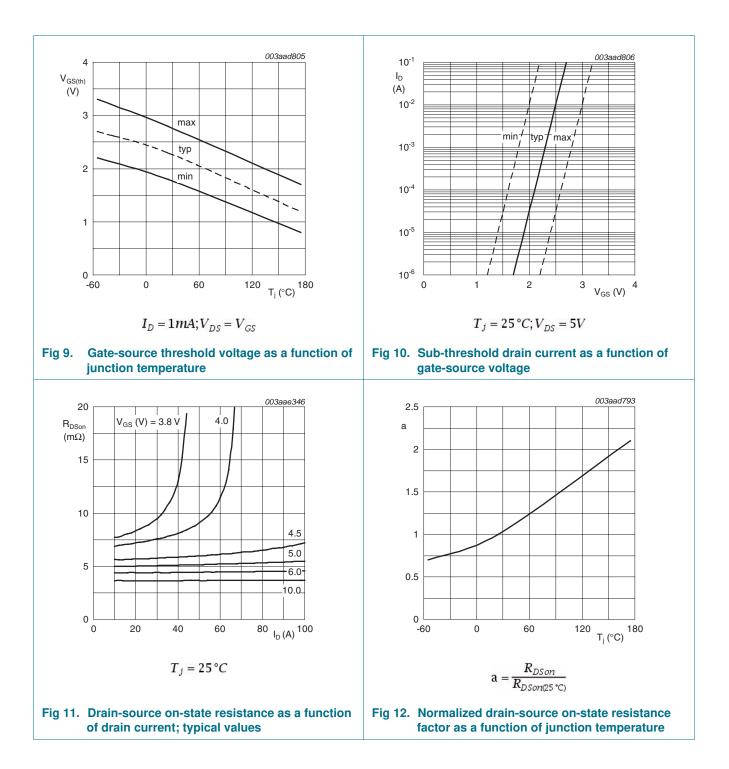
Table 6. Characteristics ...continued

Parameter

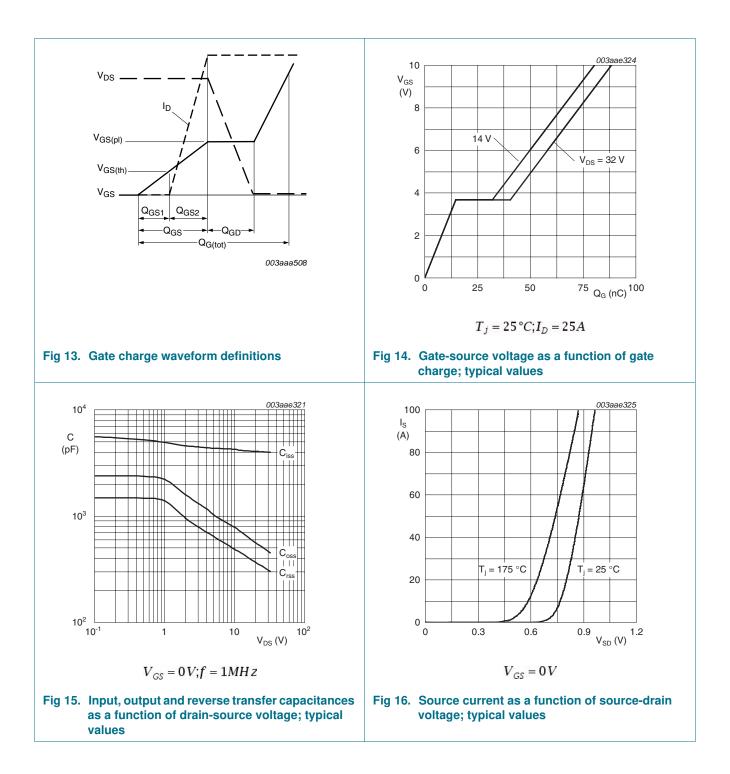
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7. Package outline

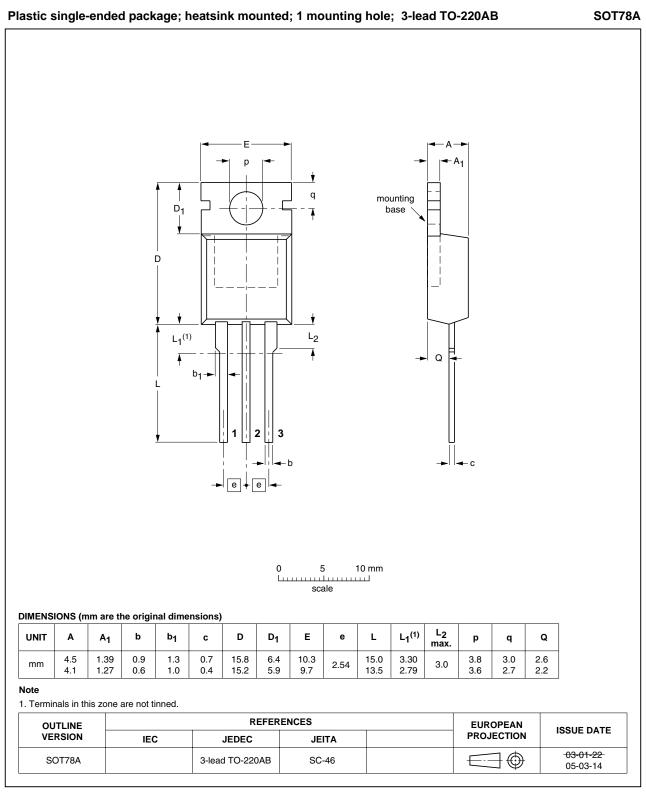


Fig 17. Package outline SOT78A (TO-220AB)

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8. Revision history

Table 7. Revision l	nistory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK654R8-40C v.3	20101012	Product data sheet	-	BUK654R8-40C v.2
Modifications:	Status changeVarious change	d from objective to product. es to content.		
BUK654R8-40C v.2	20100521	Objective data sheet	-	BUK654R8-40C v.1

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

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Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

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